

<b>Notice of References Cited</b>	Application/Control No. 09/995,696	Applicant(s)/Patent Under Reexamination WAKABAYASHI, TAKEFUMI	
	Examiner Sargon N. Nano	Art Unit 2157	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,727,135	03-1998	Webb et al.	358/1.14
*	B	US-6,173,320	01-2001	Cunningham, Randy Mark	709/220
*	C	US-2005/0021608	01-2005	Wolff, Gregory J.	709/203
*	D	US-2003/0011805	01-2003	YACoub, YOUSEF R.	358/1.15
*	E	US-5,727,135	03-1998	Webb et al.	358/1.14
*	F	US-5,706,411	01-1998	McCormick et al.	358/1.14
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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